



## Description

### JMG N-channel Advanced Mode Power MOSFET

#### Features

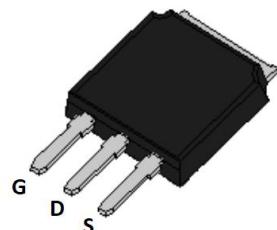
- 100V, 80A  
 $R_{DS(ON)} < 10\text{m}\Omega$  @  $V_{GS} = 10\text{V}$   
 $R_{DS(ON)} < 14\text{m}\Omega$  @  $V_{GS} = 4.5\text{V}$
- Advanced Split Gate Trench Technology
- Excellent  $R_{DS(ON)}$  and Low Gate Charge
- Lead free product is acquired

#### Application

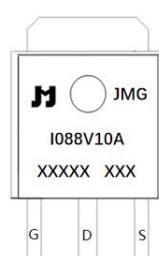
- Load Switch
- PWM Application
- Power management



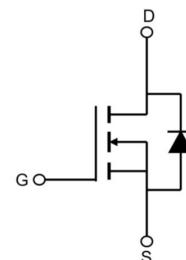
100% UIS TESTED!  
100%  $\Delta V_{ds}$  TESTED!



TO-251-3L top-view



Marking and pin Assignment



Schematic Diagram

## Package Marking and Ordering Information

Device Marking	Device	OUTLINE	Device Package	TUBE (PCS)	Inner Box (PCS)	Per Carton (PCS)
JMGI088V10A	JMGI088V10A	TAPING	TO-251-3L	75	4950	29700

## Absolute Maximum Ratings ( $T_C=25^\circ\text{C}$ unless otherwise specified)

Symbol	Parameter		Max.	Units
$V_{DSS}$	Drain-Source Voltage		100	V
$V_{GSS}$	Gate-Source Voltage		$\pm 20$	V
$I_D$	Continuous Drain Current		80	A
	$T_C = 100^\circ\text{C}$	52	A	
$I_{DM}$	Pulsed Drain Current <sup>note1</sup>		320	A
$E_{AS}$	Single Pulsed Avalanche Energy <sup>note2</sup>		90	mJ
$P_D$	Power Dissipation	$T_C = 25^\circ\text{C}$	127	W
$R_{eJC}$	Thermal Resistance, Junction to Case		1.2	$^\circ\text{C}/\text{W}$
$T_J, T_{STG}$	Operating and Storage Temperature Range		-55 to +175	$^\circ\text{C}$

**Electrical Characteristics** ( $T_J=25^\circ\text{C}$  unless otherwise specified)

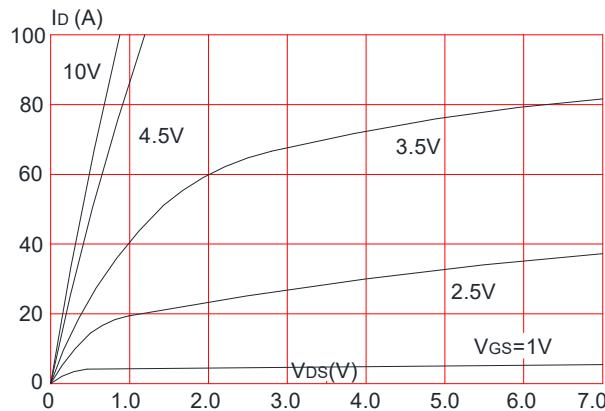
Symbol	Parameter	Test Condition	Min.	Typ.	Max.	Units
<b>Off Characteristics</b>						
$V_{(BR)DSS}$	Drain-Source Breakdown Voltage	$V_{GS}=0\text{V}$ , $I_D=250\mu\text{A}$	100	-	-	V
$I_{DSS}$	Zero Gate Voltage Drain Current	$V_{DS}=100\text{V}$ , $V_{GS}=0\text{V}$ ,	-	-	1.0	$\mu\text{A}$
$I_{GSS}$	Gate to Body Leakage Current	$V_{DS}=0\text{V}$ , $V_{GS}= \pm 20\text{V}$	-	-	$\pm 100$	nA
<b>On Characteristics</b>						
$V_{GS(\text{th})}$	Gate Threshold Voltage	$V_{DS}=V_{GS}$ , $I_D=250\mu\text{A}$	1.0	1.6	2.5	V
$R_{DS(\text{on})}$ note3	Static Drain-Source on-Resistance	$V_{GS}=10\text{V}$ , $I_D=20\text{A}$	-	7.7	10	$\text{m}\Omega$
		$V_{GS}=4.5\text{V}$ , $I_D=10\text{A}$	-	9.4	14	
<b>Dynamic Characteristics</b>						
$C_{iss}$	Input Capacitance	$V_{DS}=50\text{V}$ , $V_{GS}=0\text{V}$ , $f=1.0\text{MHz}$	-	2046	-	pF
$C_{oss}$	Output Capacitance		-	865	-	pF
$C_{rss}$	Reverse Transfer Capacitance		-	25	-	pF
$Q_g$	Total Gate Charge	$V_{DS}=50\text{V}$ , $I_D=30\text{A}$ , $V_{GS}=10\text{V}$	-	39.4	-	nC
$Q_{gs}$	Gate-Source Charge		-	5.2	-	nC
$Q_{gd}$	Gate-Drain("Miller") Charge		-	9.8	-	nC
<b>Switching Characteristics</b>						
$t_{d(on)}$	Turn-on Delay Time	$V_{DD}=50\text{V}$ , $I_D=25\text{A}$ , $R_G=6\Omega$ , $V_{GS}=10\text{V}$	-	20	-	ns
$t_r$	Turn-on Rise Time		-	5.2	-	ns
$t_{d(off)}$	Turn-off Delay Time		-	49	-	ns
$t_f$	Turn-off Fall Time		-	12	-	ns
<b>Drain-Source Diode Characteristics and Maximum Ratings</b>						
$I_S$	Maximum Continuous Drain to Source Diode Forward Current	-	-	80	A	
$I_{SM}$	Maximum Pulsed Drain to Source Diode Forward Current	-	-	320	A	
$V_{SD}$	Drain to Source Diode Forward Voltage	$V_{GS}=0\text{V}$ , $I_S=30\text{A}$	-	-	1	V
$t_{rr}$	Body Diode Reverse Recovery Time	$T_J=25^\circ\text{C}$ , $I_F=12\text{A}, dI/dt=100\text{A}/\mu\text{s}$	-	49	-	ns
$Q_{rr}$	Body Diode Reverse Recovery Charge		-	85	-	nC

Notes:1. Repetitive Rating: Pulse Width Limited by Maximum Junction Temperature

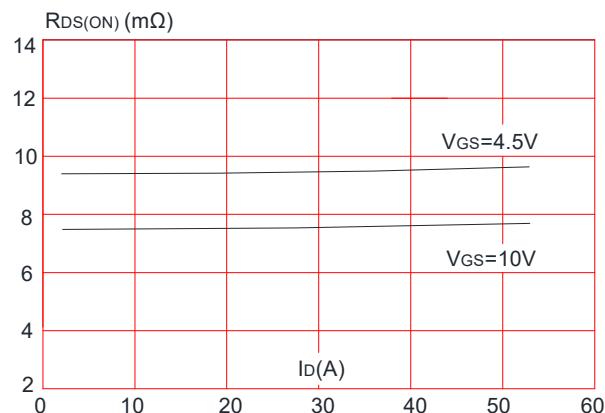
2. EAS condition:  $T_J=25^\circ\text{C}$ ,  $V_{DD}=50\text{V}$ ,  $V_G=10\text{V}$ ,  $R_G=25\Omega$ ,  $L=0.5\text{mH}$ ,  $I_{AS}=19\text{A}$ 3. Pulse Test: Pulse Width $\leq 300\mu\text{s}$ , Duty Cycle $\leq 0.5\%$

## Typical Performance Characteristics

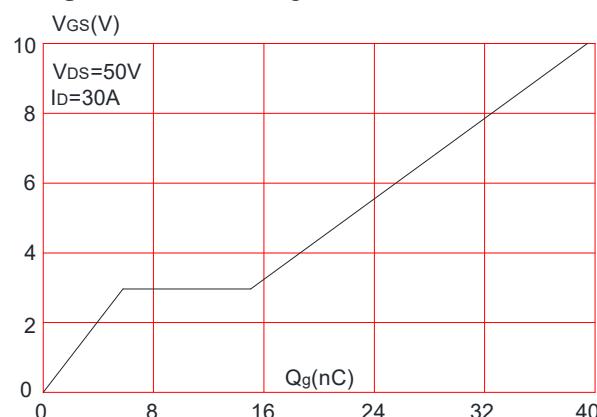
**Figure 1:** Output Characteristics



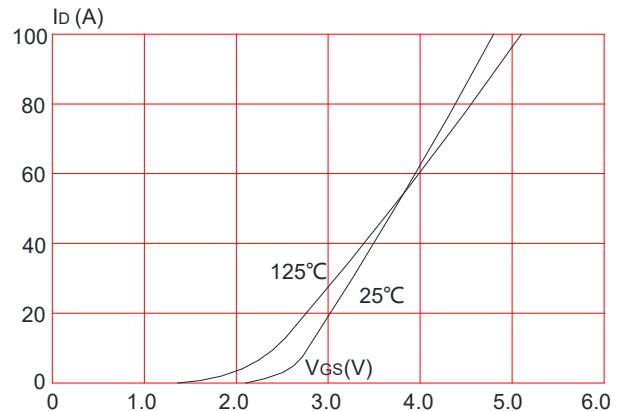
**Figure 3:** On-resistance vs. Drain Current



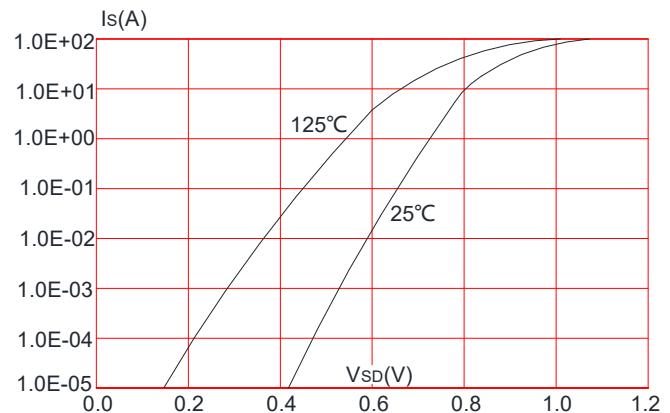
**Figure 5: Gate Charge Characteristics**



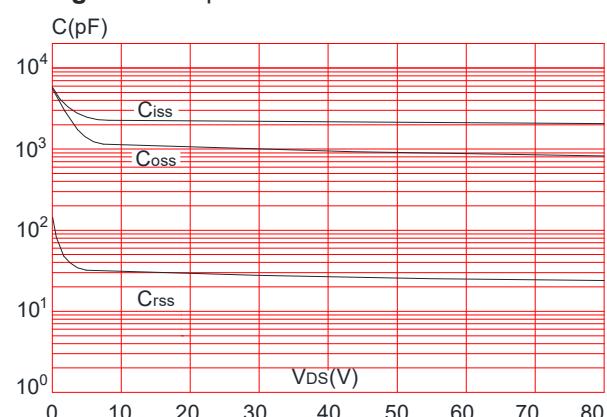
**Figure 2:** Typical Transfer Characteristics



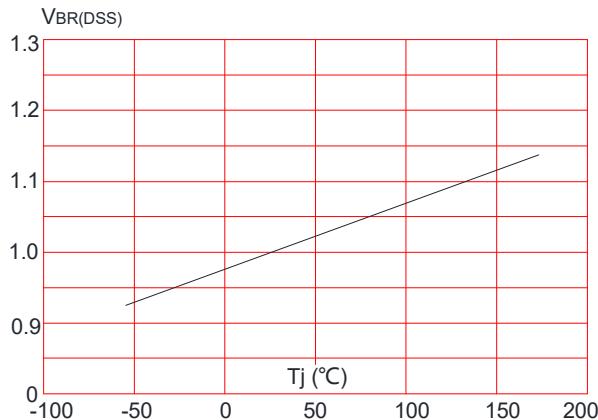
**Figure 4:** Body Diode Characteristics



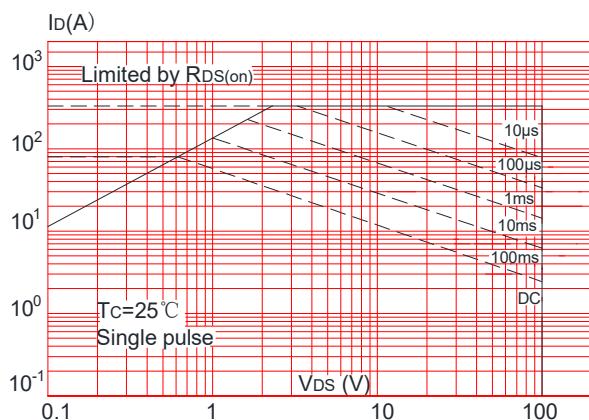
**Figure 6:** Capacitance Characteristics



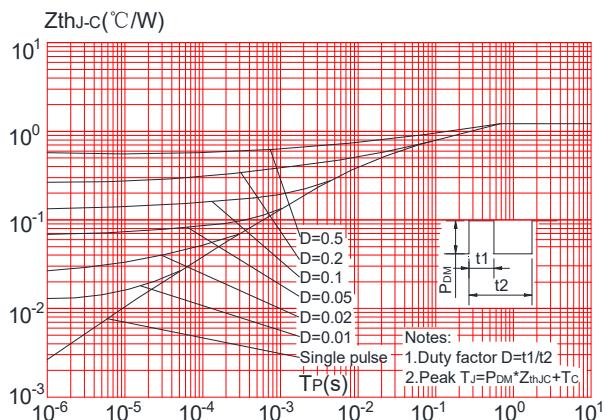
**Figure 7:** Normalized Breakdown Voltage vs. Junction Temperature



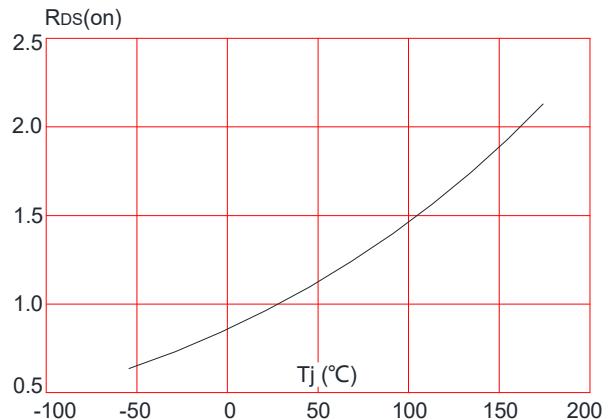
**Figure 9:** Maximum Safe Operating Area



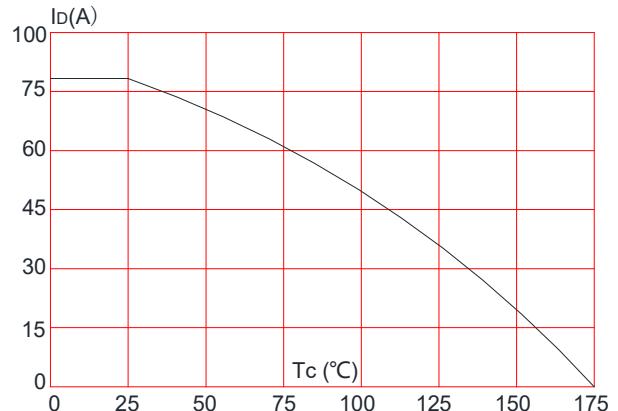
**Figure 11:** Maximum Effective Transient Thermal Impedance, Junction-to-Case



**Figure 8:** Normalized on Resistance vs. Junction Temperature



**Figure 10:** Maximum Continuous Drain Current vs. Case Temperature



## Test Circuit

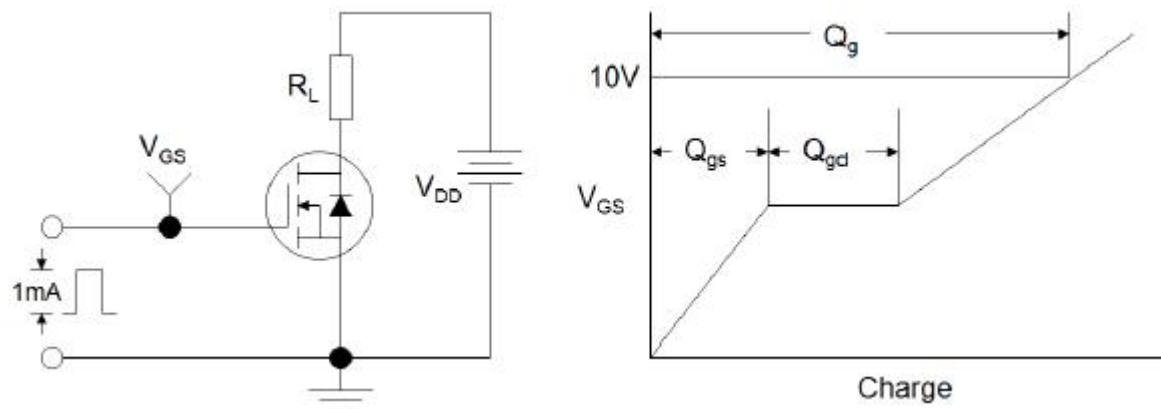


Figure1:Gate Charge Test Circuit & Waveform

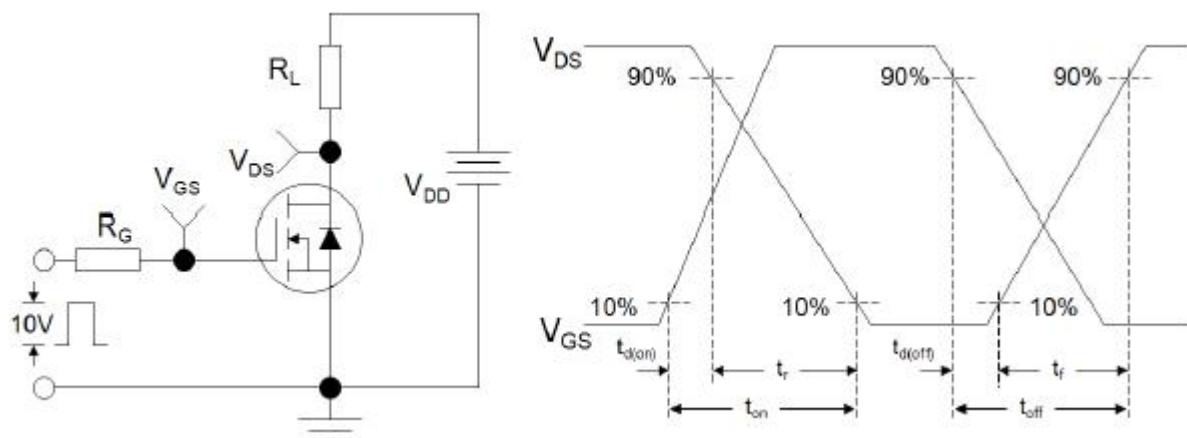


Figure 2: Resistive Switching Test Circuit & Waveforms

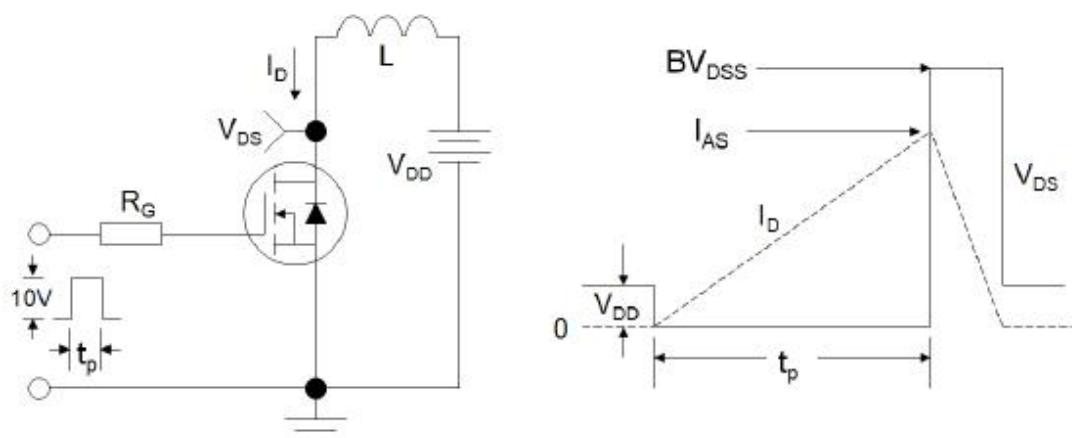
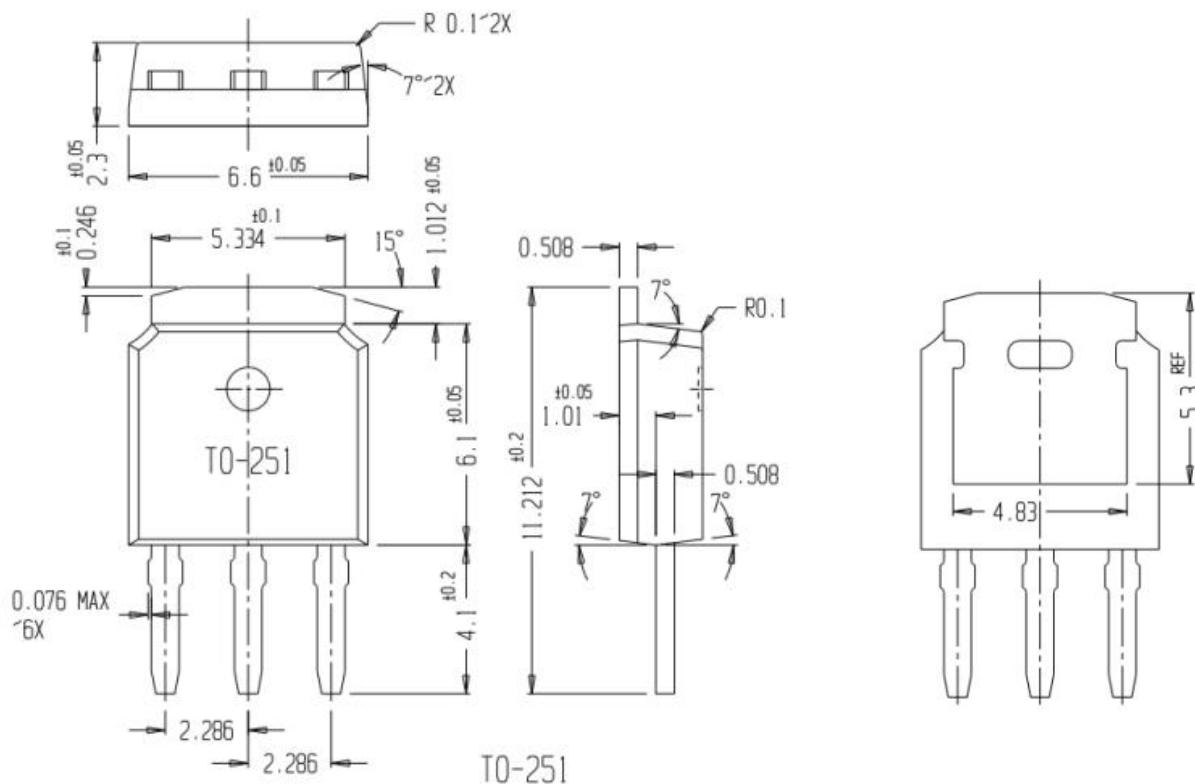


Figure 3:Unclamped Inductive Switching Test Circuit & Waveforms



## Package Mechanical Data-TO-251-3L



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